

Title	Characterization and control of femtosecond localized plasmon using spectral interferometry with SNOM or fringe-resolved autocorrelation with dark-field microscopy
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Publication	36th European Conference and Exhibition on Optical Communication (ECOC) (2010), Paper Mo.1.E.4 pp.1,3, 19-23 Sept. 2010 doi: 10.1109/ECOC.2010.5621113
Abstract	We apply two nova methods, a spectral interferometry with NSOM, and fringe-resolved-autocorrelation with dark-field microscopy in the spatio-temporal characterization of femtosecond localized plasmon at metal nanostructures. Spatio-temporal plasmon control is studied using these diagnostics.
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